

SN54HC74, SN74HC74 DUAL D-TYPE POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH CLEAR AND PRESET

SCLS094B – DECEMBER 1982 – REVISED MAY 1997

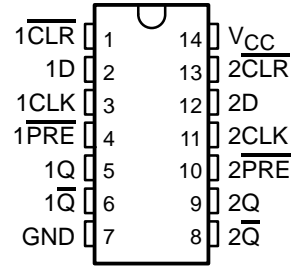
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

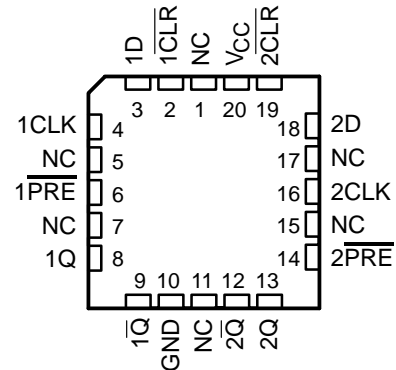
The 'HC74 contain two independent D-type positive-edge-triggered flip-flops. A low level at the preset (\overline{PRE}) or clear (\overline{CLR}) inputs sets or resets the outputs regardless of the levels of the other inputs. When \overline{PRE} and \overline{CLR} are inactive (high), data at the data (D) input meeting the setup time requirements are transferred to the outputs on the positive-going edge of the clock (CLK) pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of CLK. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs.

The SN54HC74 is characterized for operation over the full military temperature range -55°C to 125°C . The SN74HC74 is characterized for operation from -40°C to 85°C .

SN54HC74 . . . J OR W PACKAGE
SN74HC74 . . . D, DB, N, OR PW PACKAGE
(TOP VIEW)



SN54HC74 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection

FUNCTION TABLE

INPUTS				OUTPUTS	
\overline{PRE}	\overline{CLR}	CLK	D	Q	\overline{Q}
L	H	X	X	H	L
H	L	X	X	L	H
L	L	X	X	H [†]	H [†]
H	H	↑	H	H	L
H	H	↑	L	L	H
H	H	L	X	Q ₀	\overline{Q}_0

[†] This configuration is unstable; that is, it does not persist when \overline{PRE} or \overline{CLR} returns to its inactive (high) level.



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS
INSTRUMENTS**

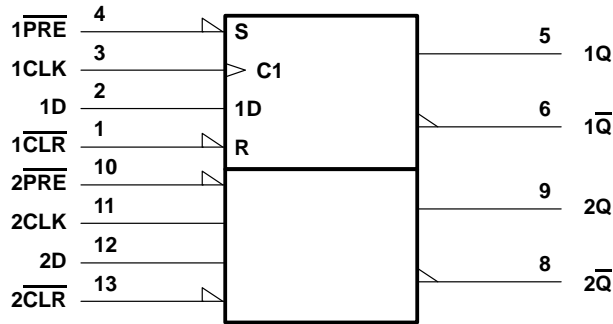
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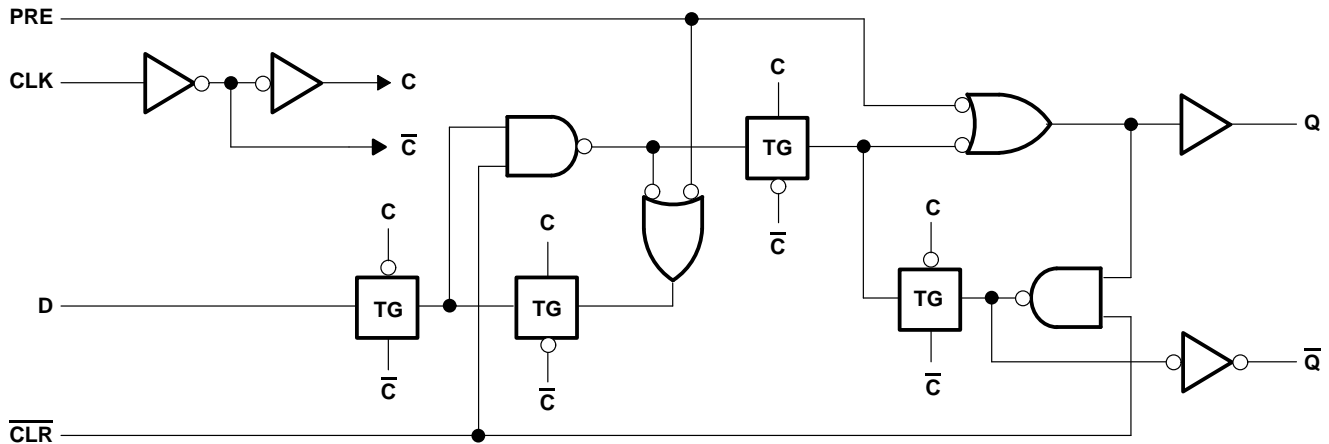
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, DB, J, N, PW, and W packages.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range‡

Supply voltage range, V_{CC}	-0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	± 20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1)	± 20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	± 25 mA
Continuous current through V_{CC} or GND	± 50 mA
Package thermal impedance, θ_{JA} (see Note 2): D package	127°C/W
DB package	158°C/W
N package	78°C/W
PW package	170°C/W
Storage temperature range, T_{stg}	-65°C to 150°C

‡ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



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recommended operating conditions

		SN54HC74			SN74HC74			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC}	Supply voltage	2	5	6	2	5	6	V
V _{IH}	High-level input voltage	V _{CC} = 2 V		1.5	1.5		V	
		V _{CC} = 4.5 V		3.15	3.15			
		V _{CC} = 6 V		4.2	4.2			
V _{IL}	Low-level input voltage	V _{CC} = 2 V		0	0.5	0	0.5	V
		V _{CC} = 4.5 V		0	1.35	0	1.35	
		V _{CC} = 6 V		0	1.8	0	1.8	
V _I	Input voltage	0	V _{CC}		0	V _{CC}		V
V _O	Output voltage	0	V _{CC}		0	V _{CC}		V
t _t	Input transition (rise and fall) time	V _{CC} = 2 V		0	1000	0	1000	ns
		V _{CC} = 4.5 V		0	500	0	500	
		V _{CC} = 6 V		0	400	0	400	
T _A	Operating free-air temperature	-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V _{CC}	T _A = 25°C			SN54HC74		SN74HC74		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V _{OH}	V _I = V _{IH} or V _{IL}	I _{OH} = -20 μA	2 V	1.9	1.998		1.9		1.9	V	
			4.5 V	4.4	4.499		4.4		4.4		
			6 V	5.9	5.999		5.9		5.9		
		I _{OH} = -4 mA	4.5 V	3.98	4.3		3.7		3.84		
		I _{OH} = -5.2 mA	6 V	5.48	5.8		5.2		5.34		
V _{OL}	V _I = V _{IH} or V _{IL}	I _{OL} = 20 μA	2 V		0.002	0.1		0.1		V	
			4.5 V		0.001	0.1		0.1			0.1
			6 V		0.001	0.1		0.1			0.1
		I _{OL} = 4 mA	4.5 V		0.17	0.26		0.4			0.33
		I _{OL} = 5.2 mA	6 V		0.15	0.26		0.4			0.33
I _I	V _I = V _{CC} or 0	6 V		±0.1	±100		±1000		±1000	nA	
I _{CC}	V _I = V _{CC} or 0, I _O = 0	6 V			4		80		40	μA	
C _i		2 V to 6 V		3	10		10		10	pF	



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timing requirements over recommended operating free-air temperature range (unless otherwise noted)

		V _{CC}	T _A = 25°C		SN54HC74		SN74HC74		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	2 V	0	6	0	4.2	0	5	MHz
		4.5 V	0	31	0	21	0	25	
		6 V	0	36	0	25	0	29	
t _w	Pulse duration	$\overline{\text{PRE}}$ or $\overline{\text{CLR}}$ low	2 V	100		150		125	ns
			4.5 V	20		30		25	
			6 V	17		25		21	
	CLK high or low	2 V	80		120		100		
		4.5 V	16		24		20		
		6 V	14		20		17		
t _{su}	Data	Data	2 V	100		150		125	ns
			4.5 V	20		30		25	
			6 V	17		25		21	
	$\overline{\text{PRE}}$ or $\overline{\text{CLR}}$ inactive	2 V	25		40		30		
		4.5 V	5		8		6		
		6 V	4		7		5		
t _h	Hold time, data after CLK↑		2 V	0		0		0	ns
			4.5 V	0		0		0	
			6 V	0		0		0	

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC}	T _A = 25°C			SN54HC74		SN74HC74		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f _{max}			2 V	6	10		4.2		5	MHz	
			4.5 V	31	50		21		25		
			6 V	36	60		25		29		
t _{pd}	$\overline{\text{PRE}}$ or $\overline{\text{CLR}}$	Q or $\overline{\text{Q}}$	2 V		70	230		345		290	ns
			4.5 V		20	46		69		58	
			6 V		15	39		59		49	
	CLK	Q or $\overline{\text{Q}}$	2 V		70	175		250		220	
			4.5 V		20	35		50		44	
			6 V		15	30		42		37	
t _t		Q or $\overline{\text{Q}}$	2 V		28	75		110		95	ns
			4.5 V		8	15		22		19	
			6 V		6	13		19		16	

operating characteristics, T_A = 25°C

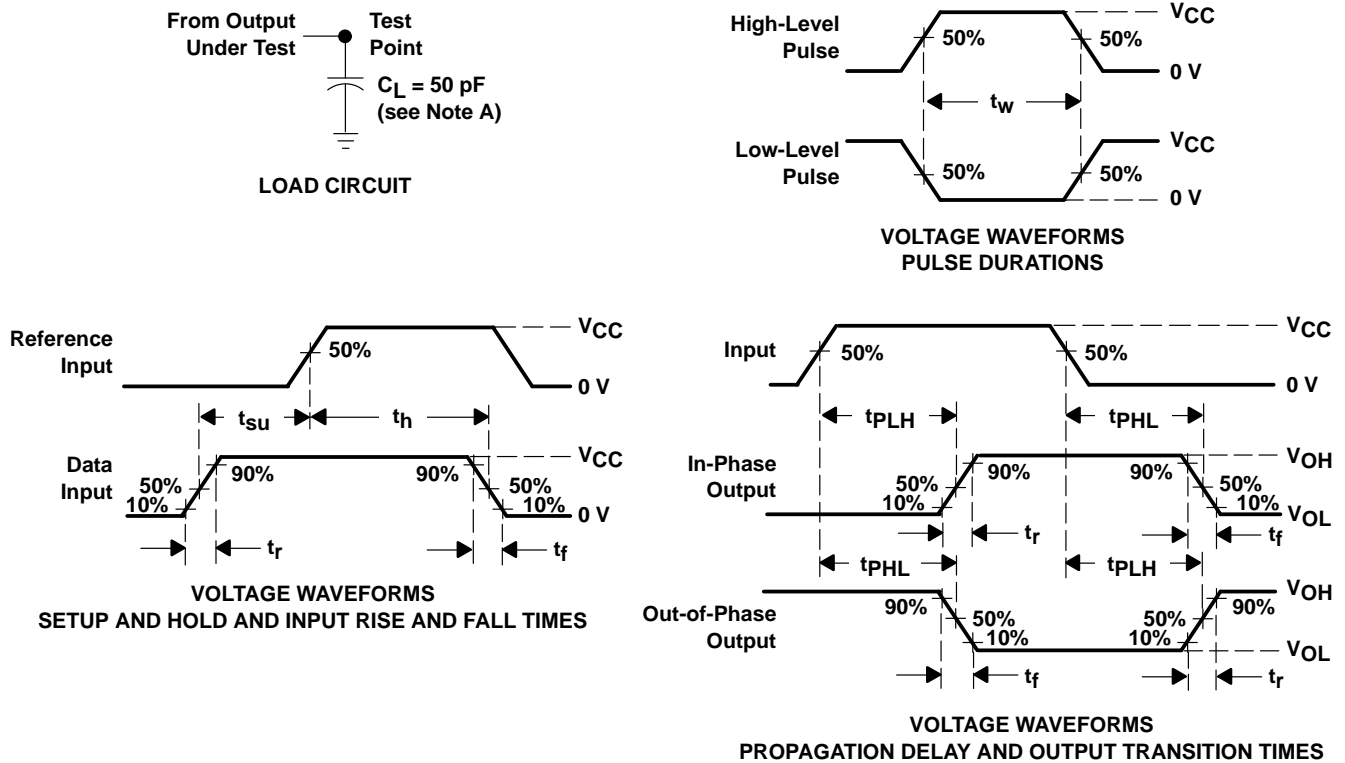
PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance per flip-flop	No load	35	pF



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PARAMETER MEASUREMENT INFORMATION



- NOTES:
- A. C_L includes probe and test-fixture capacitance.
 - B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: $PRR \leq 1 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r = 6 \text{ ns}$, $t_f = 6 \text{ ns}$.
 - C. For clock inputs, f_{max} is measured when the input duty cycle is 50%.
 - D. The outputs are measured one at a time with one input transition per measurement.
 - E. t_{PLH} and t_{PHL} are the same as t_{pD} .

Figure 1. Load Circuit and Voltage Waveforms

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